

## BAT54 BAT54A BAT54C BAT54S

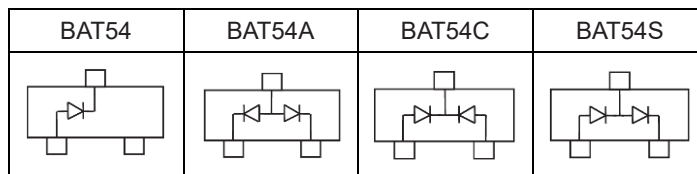
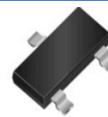
### Features

- High Current Capability
- Low Forward Voltage Drop
- Extremely Fast Switching Speed

### Applications

- SOT-23 Small Outline Plastic Package
- Epoxy UL: 94V-0
- Mounting Position: Any

### Circuit Diagram



### Absolute Maximum Ratings

Tamb=25°C unless otherwise specified

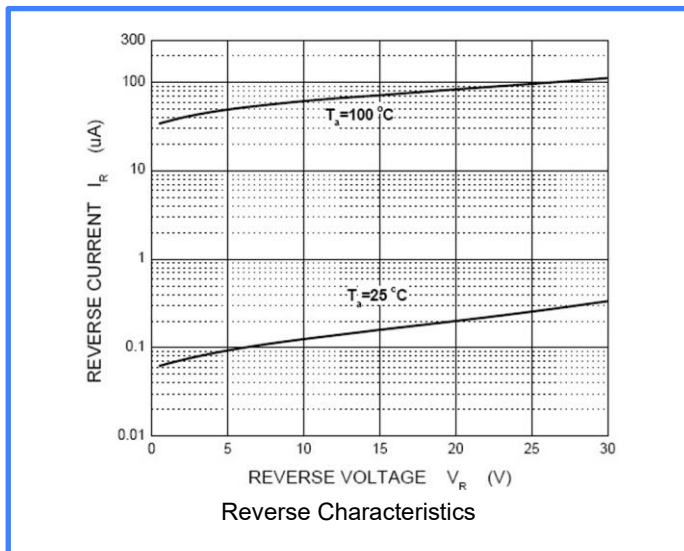
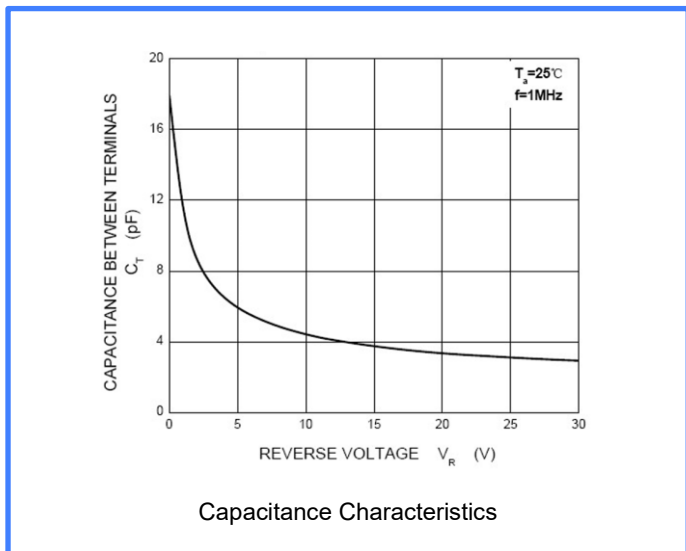
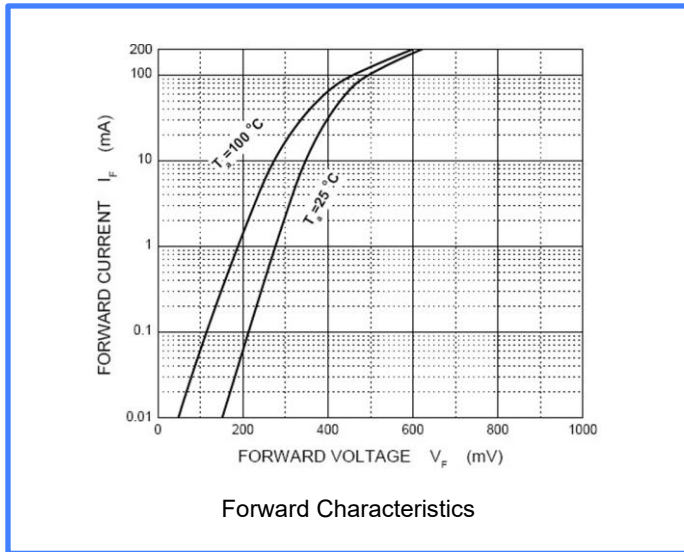
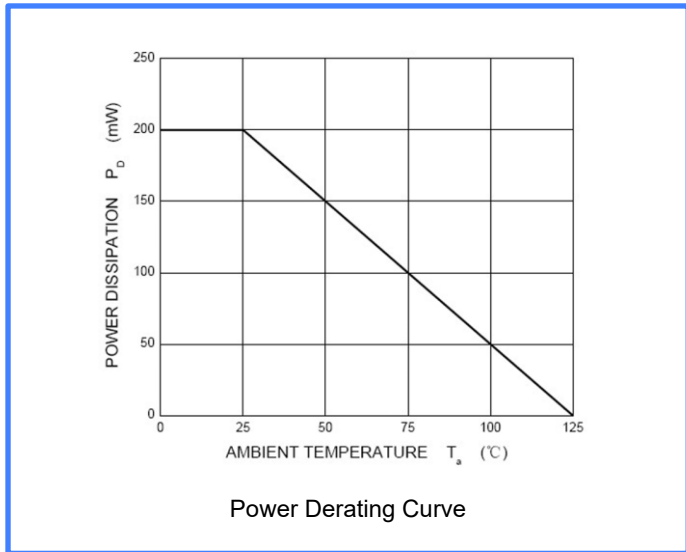
Parameter	Symbol	Value	Unit
Maximum repetitive peak reverse voltage	$V_{RRM}$	30	V
Maximum RMS voltage	$V_{RMS}$	21	V
Maximum DC blocking voltage	$V_{DC}$	30	V
Maximum average forward rectified current	$I_{FM}$	200	mA
Peak forward surge current 8.3 ms single half sine-wave	$I_{FSM}$	600	mA
Typical thermal resistance	$R_{\theta JA}$	500	°C/W
Power Dissipation	$P_D$	200	mW
Storage Temperature Range	$T_{STJ}$	-50 to +150	°C
Junction Temperature Range	$T_J$	-50 to +125	°C

### Electrical Characteristics

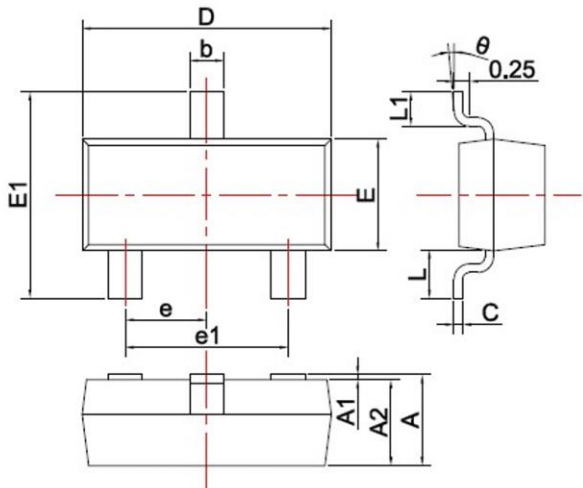
TA=25°C unless otherwise specified

Symbol	Parameter	Conditions	Min	Typ	Max	Units
$V_{F1}$	Maximum forward voltage	$I_F = 0.1\text{mA}$			240	mV
$V_{F2}$		$I_F = 1.0\text{mA}$			320	
$V_{F3}$		$I_F = 10\text{mA}$			400	
$V_{F4}$		$I_F = 30\text{mA}$			500	
$V_{F5}$		$I_F = 100\text{mA}$			1000	
$V_R$	Maximum reverse breakdown voltage	$I_R = 100\mu\text{A}$	30			V
$I_R$	Maximum reverse current	$V_R = 25\text{V}$			2	$\mu\text{A}$
$C_j$	Type junction capacitance	$V_R = 1.0\text{V}, f = 1\text{MHz}$			10	pF
$t_{rr}$	Reverse Recovery time	$I_F = I_R = 10\text{mA}$ $I_{rr} = 0.1 \times I_R$ , $R_L = 100\Omega$			5	ns

**Characteristic Curves**



**SOT23 Package Outline & Dimensions**



Symbol	Dimensions	
	Min.	Max.
A	0.900	1.150
A1	0.000	0.100
A2	0.900	1.050
b	0.300	0.500
c	0.080	0.150
D	2.800	3.000
E	1.200	1.400
e	2.250	2.550
e1	0.950typ.	
L	1.800	2.000
L1	0.550REF	
θ	0°	8°

**Disclaimer**

Specifications are subject to change without notice.

The device characteristics and parameters in this data sheet can and do vary in different applications and actual device performance may vary over time.

Users should verify actual device performance in their specific applications.